

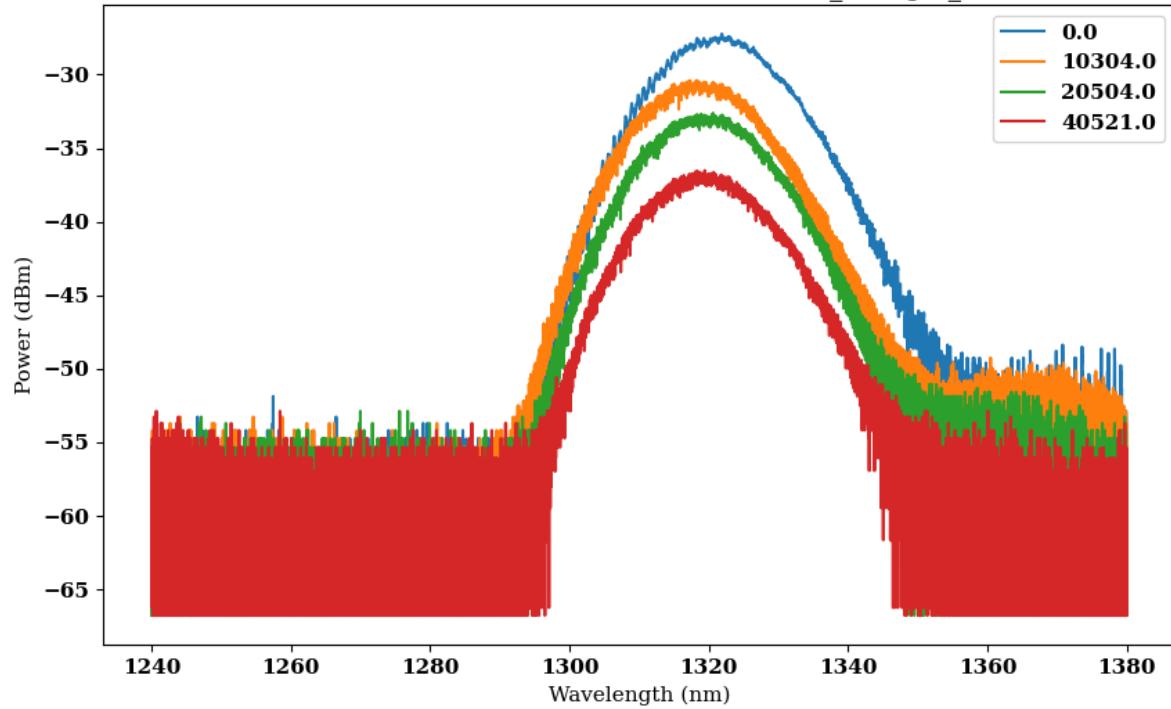
Analysis Report of EdX_May_2023_1310TE chip

Measurement date: 2023-08-28

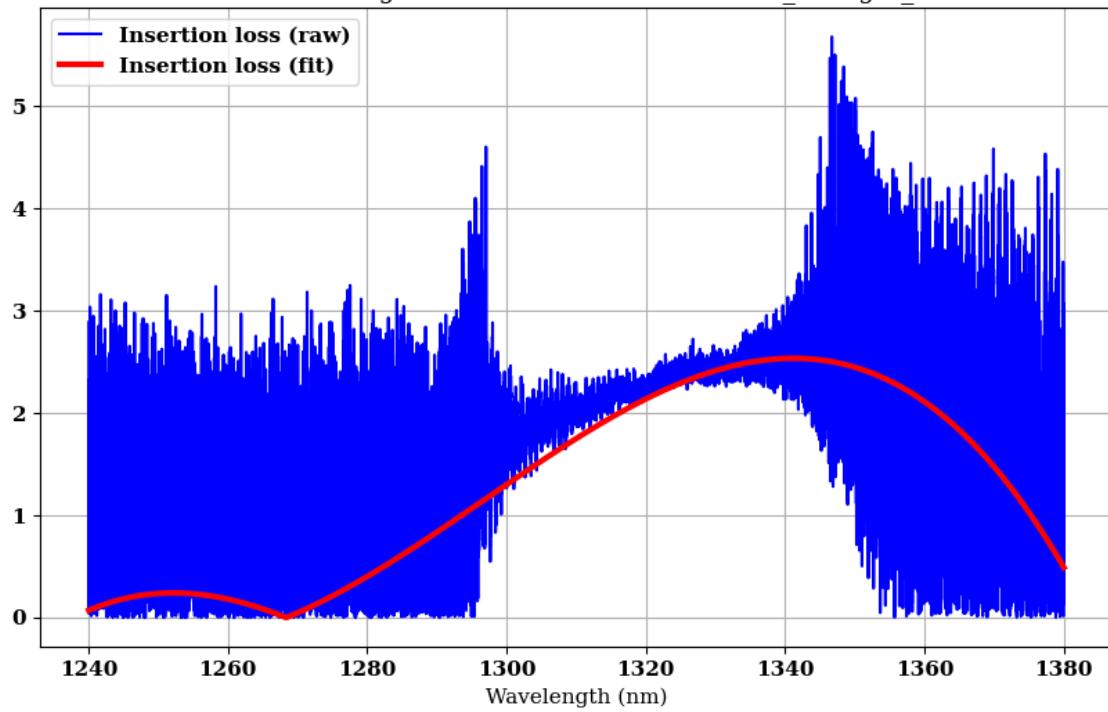
Process: ANT

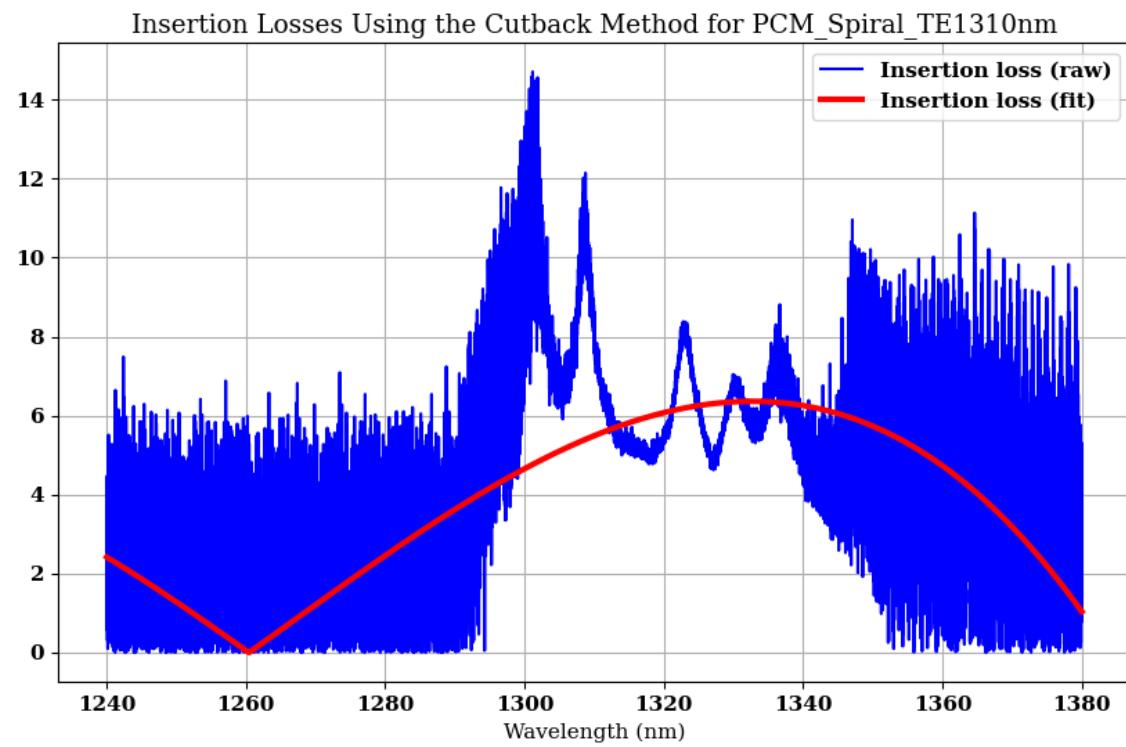
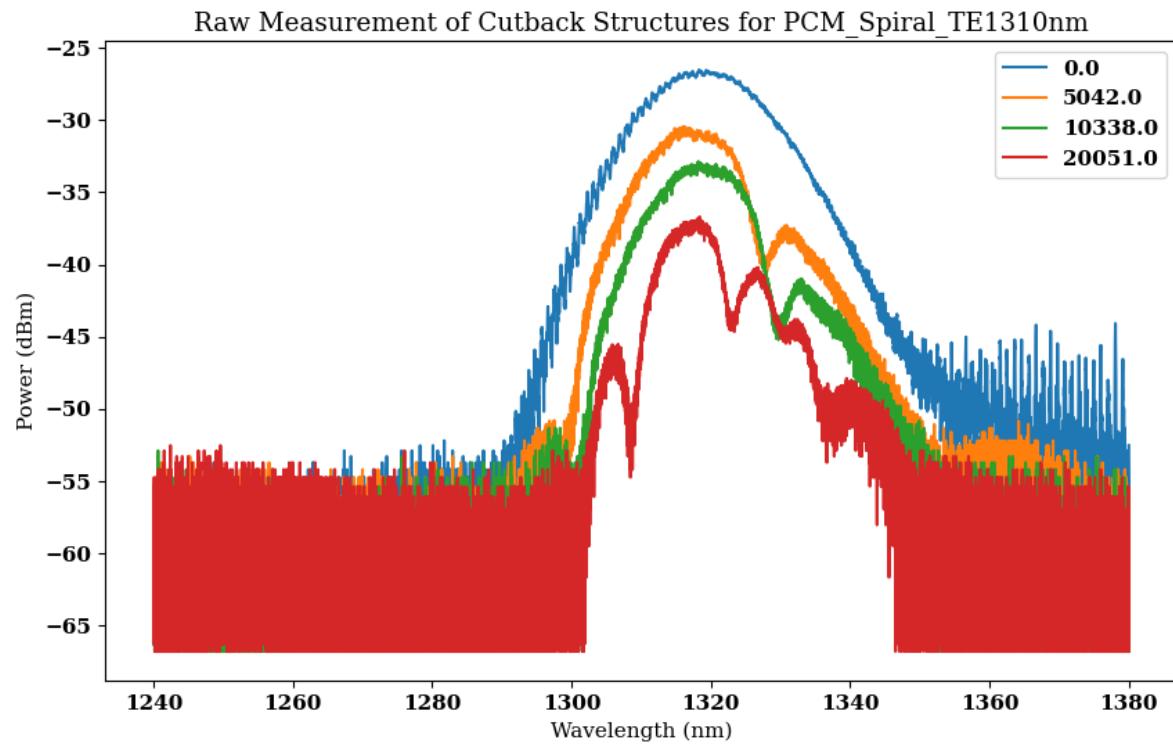
Name	Wavelength	Polarization	Data	Error	Analysis
PCM_Straight	1310nm	TE	1.75	0.24	Insertion Loss (dB/cm)
PCM_Spiral	1310nm	TE	5.49	2.67	Insertion Loss (dB/cm)
PCM_YBranch	1310nm	TE	0.1	0.11	Insertion Loss (dB/device)
PCM_ContraDC	1310nm	TE	0.21	0.02	Insertion Loss (dB/device)
PCM_Bragg_Period	1310nm	TE	-0.71	N/A	Bragg Drift (nm)
PCM_GIndex	1310nm	TE	4.12	0.8	Group Index

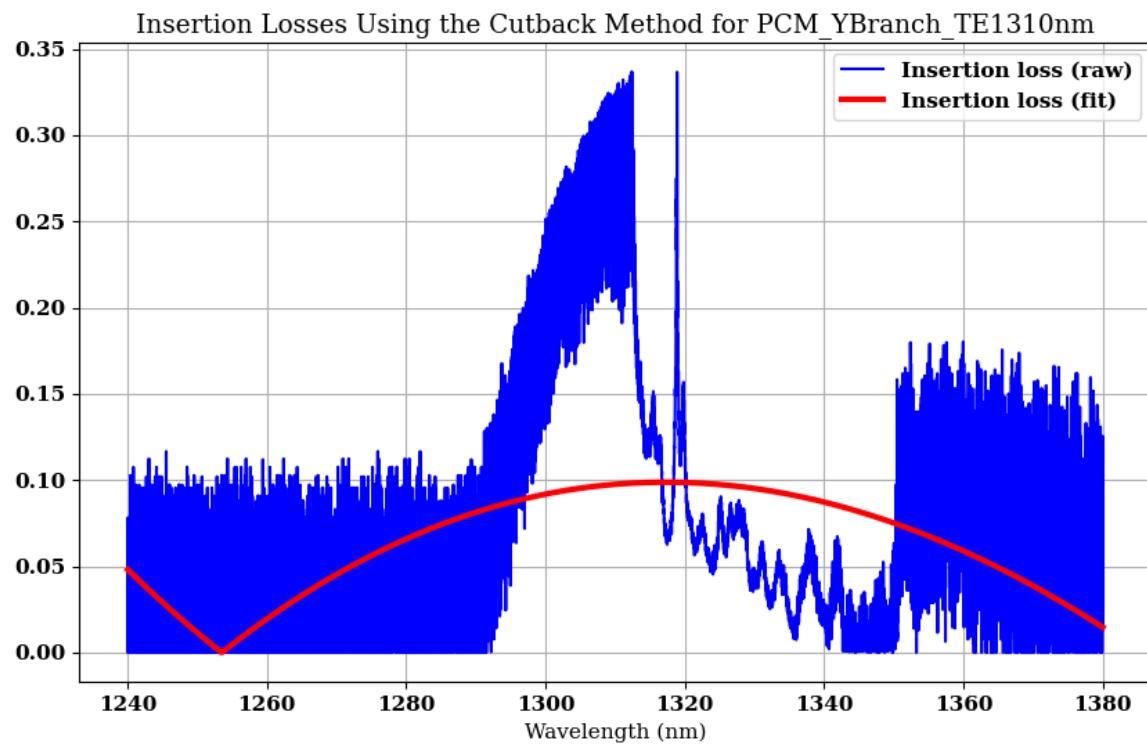
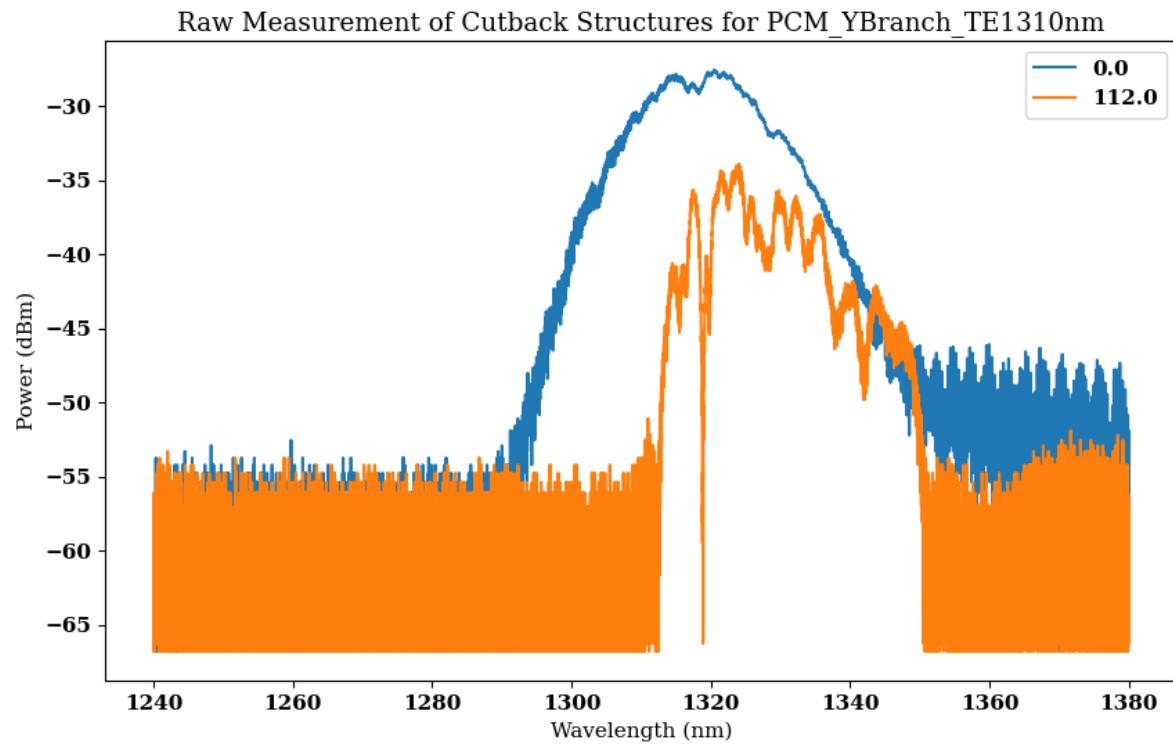
Raw Measurement of Cutback Structures for PCM_Straight_TE1310nm



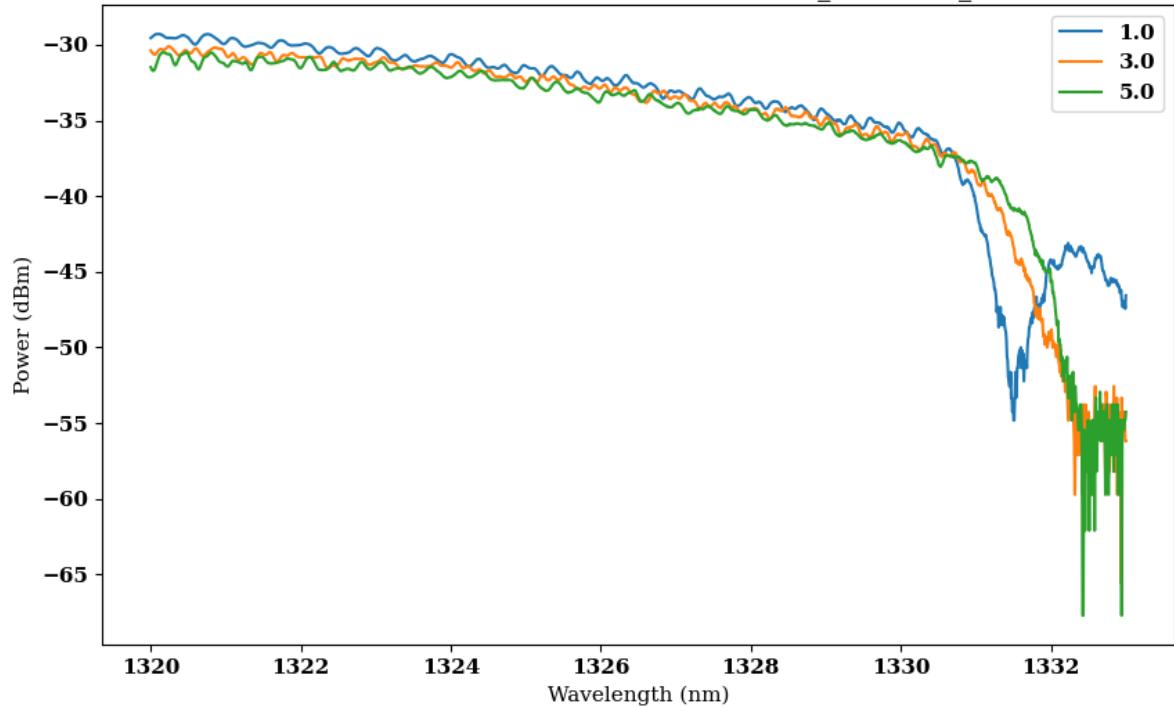
Insertion Losses Using the Cutback Method for PCM_Straight_TE1310nm



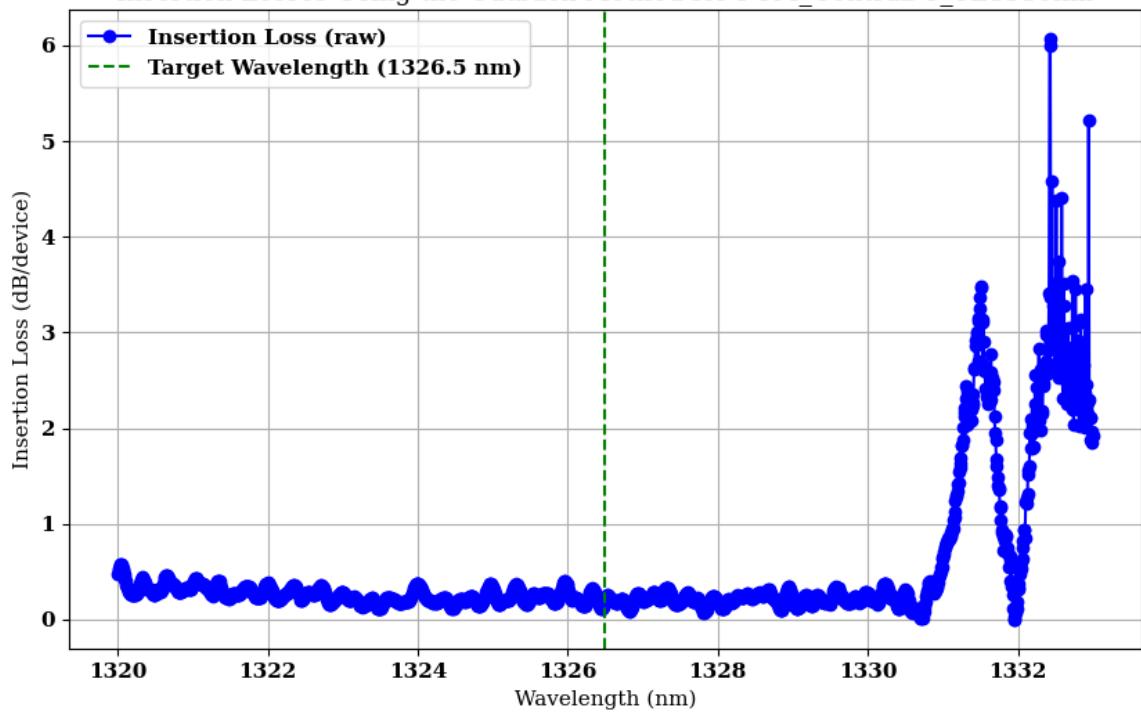




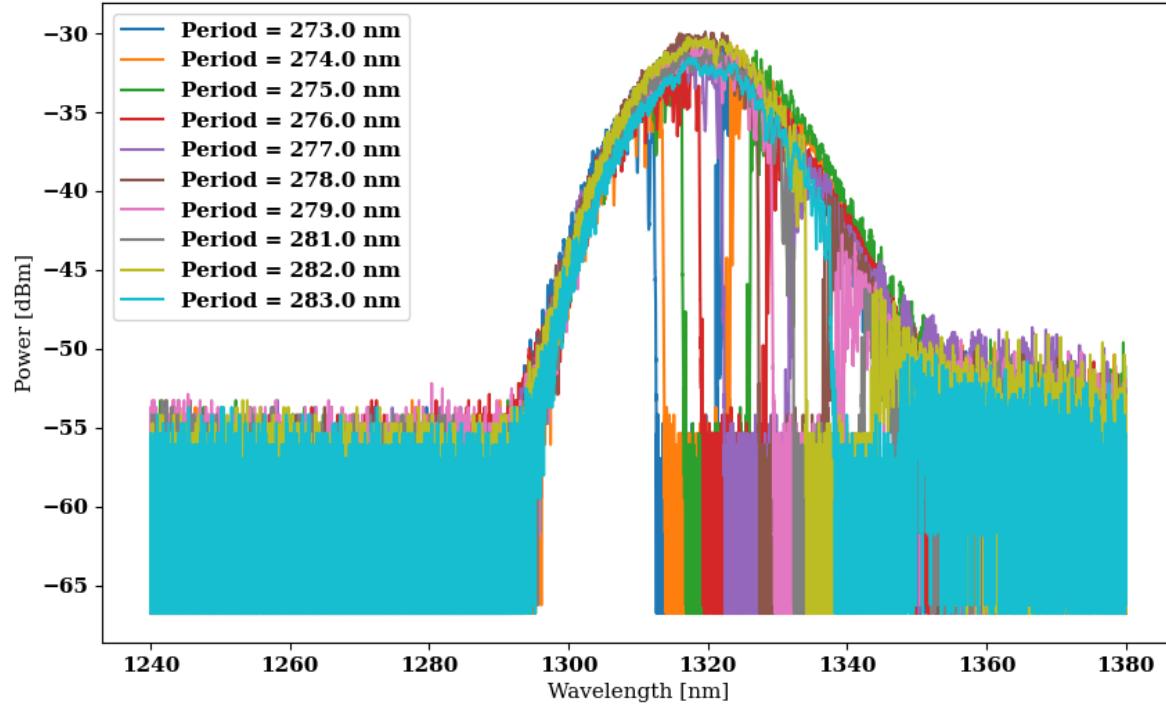
Raw Measurement of Cutback Structures for PCM_ContraDC_TE1310nm



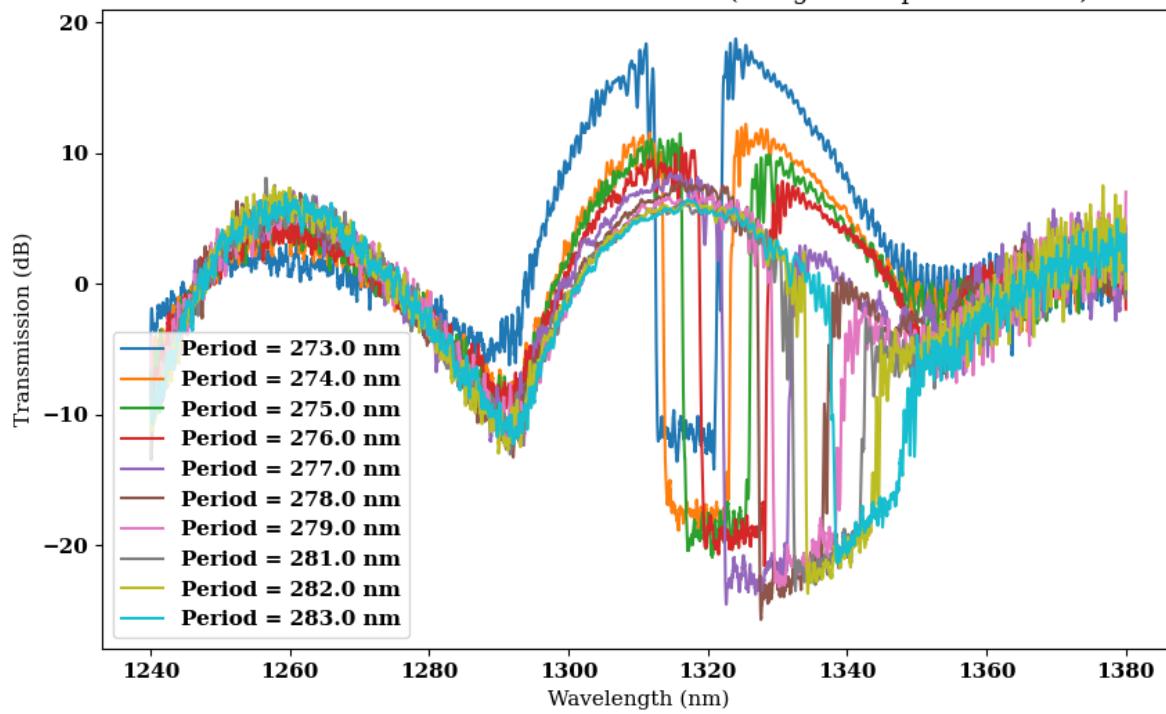
Insertion Losses Using the Cutback Method for PCM_ContraDC_TE1310nm



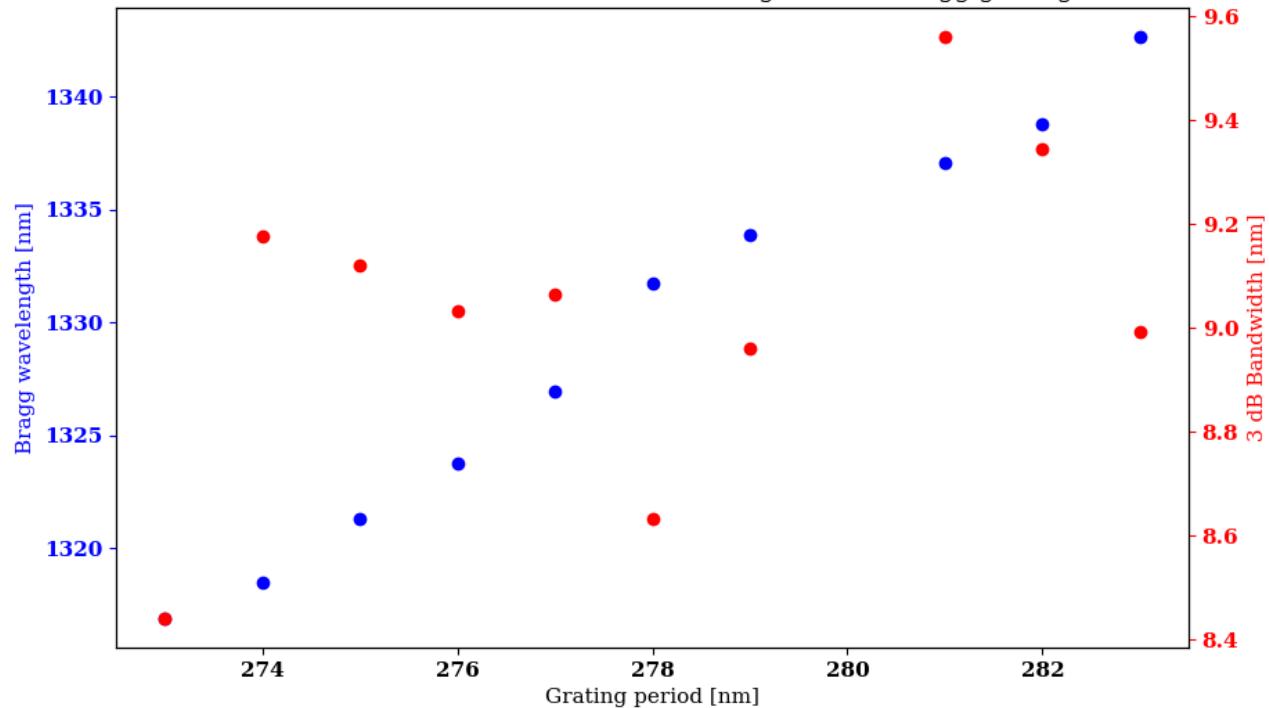
Raw measurement of all structures



Calibrated measurement of all structures (using envelope calibration)



Extracted bandwidth and central wavelength of the Bragg gratings



Comparison of Bragg wavelength between simulation and experiment.

